

Notice of References Cited	Application/Control No. 09/868,573	Applicant(s)/Patent Under Reexamination ZEN, MITSUO	
	Examiner Lynne Edmondson	Art Unit 1725	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,666,078	05-1987	Ohno, Yoshihiro	228/124.1
*	B	US-6,152,597	11-2000	Potega, Patrick H.	374/185
*	C	US-5,609,287	03-1997	Izuta et al.	228/123.1
*	D	US-5,629,559	05-1997	Miyahara, Kenichiro	257/666
*	E	US-6,095,404	08-2000	McAndrew, Charlie	228/180.1
*	F	US-2001/0052643	12-2001	SUGIHARA et al.	257/692
*	G	US-5,521,432	05-1996	Tsuji et al.	257/677
*	H	US-4,331,258	05-1982	Geschwind, Gary I.	220/359.5
*	I	US-6,084,775	07-2000	Bartley et al.	361/705
*	J	US-RE34,484	12-1993	Nagashima et al.	428/621
	K	US-4,385,976	05-1983	Schuster-Wolden et al.	204/192.29
	L	US-5,080,980	01-1992	Sakaguchi et al.	428/610
	M	US-6,652,990	11-2003	Carey et al.	428/647

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP-10-102283-A	04-1998	Japan	Obata et al.	
*	O	JP-09-293958-A	11-1997	Japan	Sato	
*	P	JP-02-270990-A	11-1990	Japan	Murata et al.	
*	Q	DT-2340423-A!	02-1975	Germany	Siemens AG	
*	R	JP-63-86254-A	04-1988	Japan	Suzuki et al.	
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.